TENTATIVE

TOSHIBA BIPOLAR LINEAR INTEGRATED CIRCUIT SILICON MONOLITHIC

TA8316AS

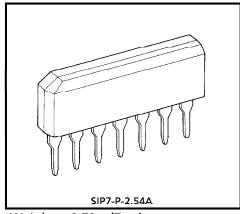
IGBT GATE DRIVER

TA8316AS is a dedicated IC integrating IGBT gate drive circuits on a single chip.

A high current directly drives IGBT.

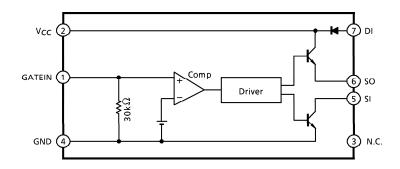
FEATURES

- Can directly control from a microcontroller
- Can directly drive the IGBT gate using a high current.
 Source current: 200mA (max), sink current 1A (max)
- Incorporates a diode to protect the IGBT gate at power on.



Weight: 0.72g (Typ.)

BLOCK DIAGRAM

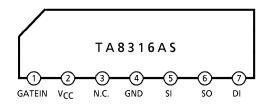


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PIN CONNECTION



PIN FUNCTIONS

PIN No.	PIN NAME	FUNCTION		
1	GATEIN	Gate Signal Input Pin		
2	Vcc	System Power Supply		
3	N.C.	Not Connected		
4	GND	GND		
5	SI	IGBT Gate Drive Pin 1 (Sink Side)		
6	SO	IGBT Gate Drive Pin 2 (Source Side)		
7	DI	IGBT Gate Protector Diode Pin		

MAXIMUM RATINGS (Ta = 25° C)

CHARACTERISTIC	SYMBOL	RATING	UNIT
Collector Supply Voltage	Vcc	25	V
Input Voltage	V _{in}	GND – 0.3~V _{CC} + 0.3	V
Operating Temperature	T _{opr}	- 20~85	°C
Storage Temperature	T _{stg}	- 55~150	°C
Power Dissipation *	PD	925	mW

^{*} When Ta>25°C, P_D decreases 7.4mW per degree.

ELECTRICAL CHARACTERISTICS (Ta = 25° C, Unless otherwise specified, $V_{CC} = 20V$)

CHARACTERISTIC	SYMBOL	TEST CIR- CUIT	TEST CONDITION	MIN.	TYP.	MAX.	UNIT		
Supply Voltage Block									
Operating Supply Voltage Range	VCC	_	_	7	_	24	V		
Current Consumption 1	^I CC1	_	V _{CC} = 20V, GATEIN = "H", No Load	0.7	1.25	1.9	mA		
Current Consumption 2	l _{CC2}	_	V _{CC} = 20V, GATEIN = "L", No Load	4.2	6.25	8.8	mA		
(GATEIN Pin)									
Input Dynamic Range	V _{in} GATEIN	_	_	0	_	V _C C – 2.2	٧		
Threshold Voltage 1	V _{th} GATE1	_	GATE Signal L→H	_	2.63	3	V		
Threshold Voltage 2	V _{th} GATE2	_	GATE Signal H→L	1.5	2.27	_	V		
Input Current	I _{in} GATE	_	V _{in} = 5V	125	167	249	μΑ		
Input Frequency (Reference)	f _{in} GATE		When Load C = 5600pF, R = $10k\Omega$ Connected	_	_	50	kHz		
(SI Pin)									
"L" Level Output Voltage 1	V _{OL} SI1	_	VGATEIN = 0V, I _{OL} = 30mA	_	_	0.7	٧		
"L" Level Output Voltage 2	V _{OL} SI2	_	VGATEIN = 0V, I _{OL} = 1A	_	_	2	V		
"L" Level Output Voltage 3	V _{OL} SI3	_	V _{CC} = 7V, VGATEIN = 0V, I _{OL} = 30mA	_	_	1	V		
"L" Level Output Voltage 4 (Output Voltage At Low Supply Voltage)	V _{OL} SI4	_	2V≦V _{CC} <7V, VGATEIN=0V, No Load	_	_	1	٧		
"L" Level Output Voltage 5 (Output Voltage At Low Supply Voltage)	V _{OL} SI5	_	$2V \le V_{CC} < 7V$, VGATEIN = 0V, $I_{OL} = 30$ mA	_	_	2	>		
Off Leakage Current	loff SI	_	VGATEIN = 6V, V _{in} = 20V	- 1		1	μΑ		
(SO Pin)									
"H" Level Output Voltage 1	V _{OH} SO1		VGATEIN = 6V, IOH = -30mA	V _{CC} - 2	_	_	٧		
"H" Level Output Voltage 2	V _{OH} SO2	_	VGATEIN = 6V, I _{OH} = -200mA	V _{CC} – 5	_	_	V		
Off Leakage Current	loff SO	_	VGATEIN = 0V, V _{in} = 0V	_ 1	_	1	μΔ		
(DI Pin)									
Input Clamp Voltage 1	V _F DI1	_	I _{in} = 500mA	_	_	V _C C + 1.5	V		
Input Clamp Voltage 2	V _{F DI2}	_	V _{CC} = 0V, I _{in} = 300mA	_	_	V _{CC} + 1.0	V		

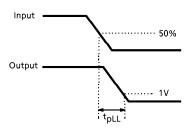
AC CHARACTERISTICS	$Ta = 25^{\circ}C$	Unless	otherwise	specified,	$V_{CC} = 20V$
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CHARACTERISTIC	SYMBOL	TEST CIR- CUIT	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Propagation Delay Time 1	t _{PLL}	_	See test circuit diagram	_	_	2	μs
Propagation Delay Time 2	^t PHH	_	See test circuit diagram	_	_	2	μs
Output Fall Time	tf	_	See test circuit	_	_	0.5	μs

AC CHARACTERISTICS TEST CONDITIONS

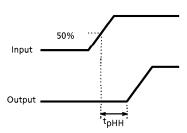
① Propagation delay time 1 (tpLL)

Time from input of "L" level to GATEIN pin until output reaches 1V



2 Propagation delay time 2 (tpHH)

Time from input of "H" level to GATEIN pin until output starts to rise



3 Output fall time (t_f)

Output fall time from 90% to 10%

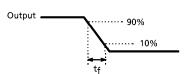
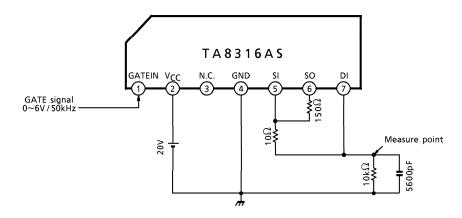
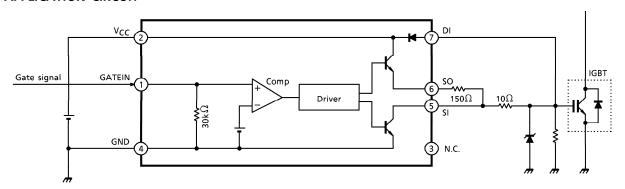


DIAGRAM OF AC CHARACTERISTICS TEST CIRCUIT

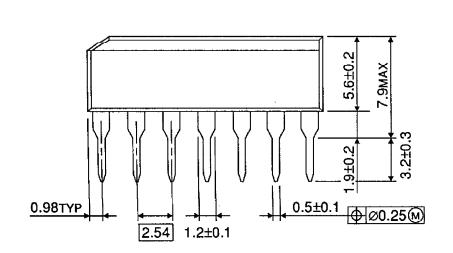


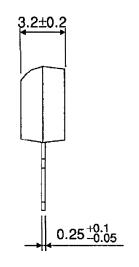
APPLICATION CIRCUIT

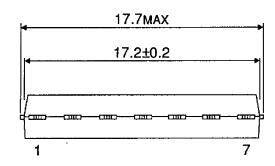


OUTLINE DRAWING

SIP7-P-2.54A Unit: mm







Weight: 0.72g (Typ.)